

PATENT NUMBER,

U.S. UTILITY Patent Application

O.I.P.E.		PATENT DATE
SCANNED	PD ² Q.A. <i>RG</i>	

APPLICATION NO. 09/629141	CONT/PRIOR F	CLASS 349 382	SUBCLASS 124	ART UNIT 2871 2625	EXAMINER EXAMINER S. C. Chou
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APPLICANTS

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TITLE

Method of erasing repeated patterns and pattern defect inspection device

PTO-2040
12/99

ISSUING CLASSIFICATION												
ORIGINAL				CROSS REFERENCE(S)								
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)							
INTERNATIONAL CLASSIFICATION												

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<input type="checkbox"/> TERMINAL DISCLAIMER	DRAWINGS Sheets Drwg. Figs. Drwg. Print Fig.		CLAIMS ALLOWED Total Claims Print Claim for O.G.	
	_____ (Assistant Examiner) (Date)		NOTICE OF ALLOWANCE MAILED _____	
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